CY62148B

512K x 8 Static RAM

Features

- **4.5V–5.5V operation**
- **CMOS for optimum speed/power**
- **Low active power**
  - **— 165 mW (max.)**
- **Low standby power (L version)**
  - **— 110 µW (max.)**
- **Automatic power-down when deselected**
- **TTL-compatible inputs and outputs**
- **Easy memory expansion with $\overline{CE}$ and $\overline{OE}$ options**

Functional Description

The CY62148 is a high-performance CMOS static RAM organized as 524,288 words by 8 bits. Easy memory expansion is provided by an active LOW Chip Enable ($\overline{CE}$), an active LOW Output Enable ($\overline{OE}$), and three-state drivers. This device has an automatic power-down feature that reduces power consumption by more than 99% when deselected.

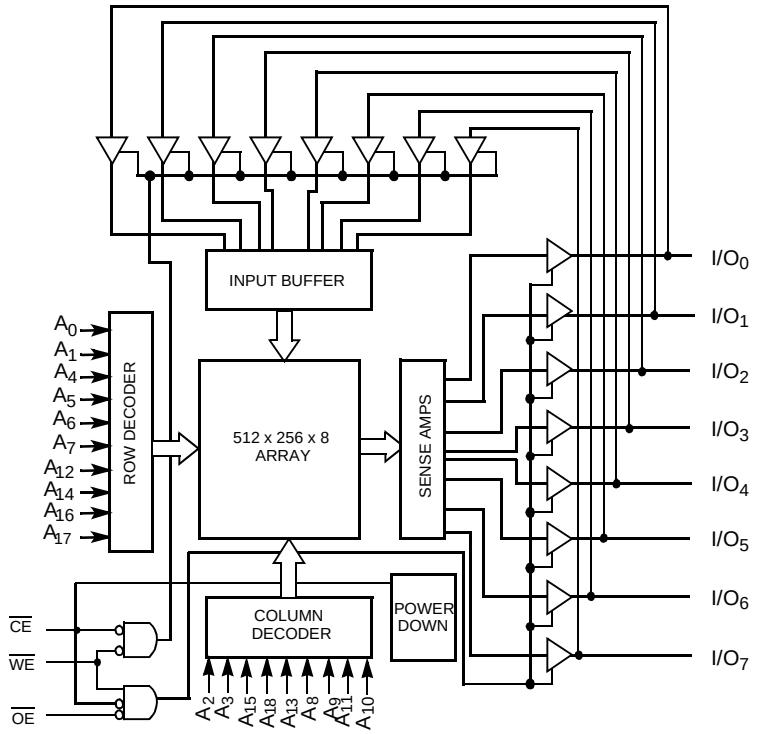
Writing to the device is accomplished by taking Chip Enable ($\overline{CE}$) and Write Enable ($\overline{WE}$) inputs LOW. Data on the eight I/O pins (I/O_0 through I/O_7) is then written into the location specified on the address pins (A_0 through A_{18}).

Reading from the device is accomplished by taking Chip Enable ($\overline{CE}$) and Output Enable ($\overline{OE}$) LOW while forcing Write Enable ($\overline{WE}$) HIGH for read. Under these conditions, the contents of the memory location specified by the address pins will appear on the I/O pins.

The eight input/output pins (I/O_0 through I/O_7) are placed in a high-impedance state when the device is deselected ($\overline{CE}$ HIGH), the outputs are disabled ($\overline{OE}$ HIGH), or during a write operation ($\overline{CE}$ LOW, and $\overline{WE}$ LOW).

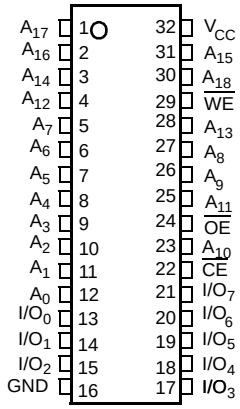
The CY62148 is available in a standard 32-pin 450-mil-wide body width SOIC and 32-pin TSOP II packages.

Logic Block Diagram

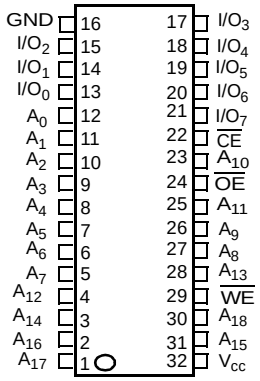


Pin Configuration

Top View
SOIC
TSOP II



Top View
Reverse
TSOP II



Selection Guide

			CY62148BLL-55	CY62148BLL-70	Unit
Max Access Time			55	70	ns
Max Operating Current (I_{cc})	Commercial	LL	30	20	mA
	Industrial		30	20	mA
Max CMOS Standby Current (I_{SB2})	Commercial	LL	20	20	µA
	Industrial		20	20	µA

Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature ..... –65°C to +150°C

Ambient Temperature with Power Applied..... –55°C to +125°C

Supply Voltage on V_{CC} to Relative GND ..... –0.5V to +7.0V

DC Voltage Applied to Outputs in High Z State[1] ..... –0.5V to V_{CC} +0.5V

DC Input Voltage[1]..... –0.5V to V_{CC} +0.5V

Current into Outputs (LOW) ..... 20 mA

Static Discharge Voltage..... 2001V (per MIL-STD-883, Method 3015)

Latch-Up Current..... >200 mA

Operating Range

Range	Ambient Temperature[2]	V_{CC}
Commercial	0°C to +70°C	4.5V–5.5V
Industrial	–40°C to +85°C	

Notes:
1. V_{IL} (min.) = –2.0V for pulse durations of less than 20 ns.
2. T_A is the "Instant On" case temperature.

Electrical Characteristics Over the Operating Range

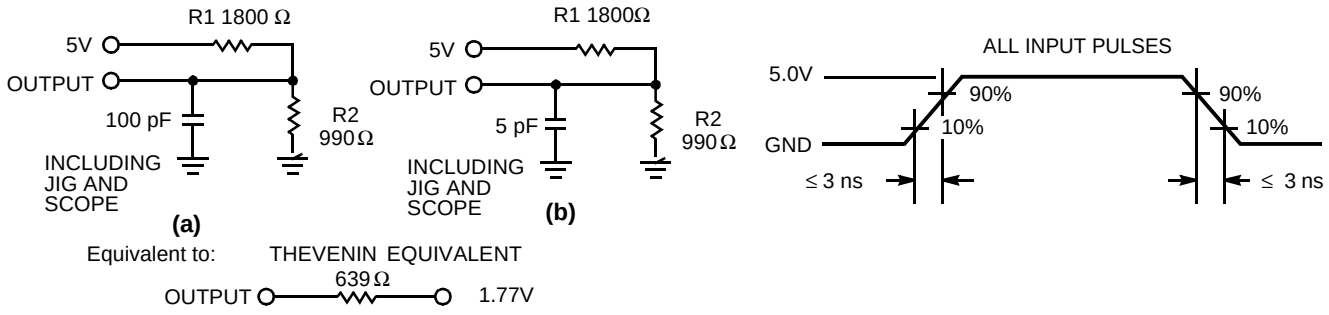
Parameter	Description	Test Conditions			CY62148B-55			CY62148B-70			Unit
					Min.	Typ.[3]	Max.	Min.	Typ.(3)	Max	
V_{OH}	Output HIGH Voltage	V_{CC} = Min., I_{OH} = – 1 mA			2.4			2.4			V
V_{OL}	Output LOW Voltage	V_{CC} = Min., I_{OL} = 2.1 mA					0.4			0.4	V
V_{IH}	Input HIGH Voltage				2.2		V_{CC}+ 0.3	2.2		V_{CC}+ 0.3	V
V_{IL}	Input LOW Voltage[1]				–0.3		0.8	–0.3		0.8	V
I_{IX}	Input Load Current	GND ≤ V_I ≤ V_{CC}			–1		+1	–1		+1	µA
I_{OZ}	Output Leakage Current	GND ≤ V_I ≤ V_{CC}, Output Disabled			–1		+1	–1		+1	µA
I_{CC}	V_{CC} Operating Supply Current	V_{CC} = Max., I_{OUT} =0 mA, f = f_{MAX} = $1/t_{RC}$	Ind'l	LL			30			20	mA
I_{SB1}	Automatic CE Power-Down Current —TTL Inputs	Max. V_{CC}, $\overline{CE}$ ≥ V_{IH} V_{IN} ≥ V_{IH} or V_{IN} ≤ V_{IL}, f = f_{MAX}	Ind'l	LL			2.5			1.5	mA
I_{SB2}	Automatic CE Power-Down Current —CMOS Inputs	Max. V_{CC}, $\overline{CE}$ ≥ V_{CC} – 0.3V, V_{IN} ≥ V_{CC} – 0.3V, or V_{IN} ≤ 0.3V, f = 0	Ind'l	LL		4	20		4	20	µA
I_{CC}	V_{CC} Operating Supply Current	V_{CC} = Max., I_{OUT} =0 mA, f = f_{MAX} = $1/t_{RC}$	Com	LL			30			20	mA
I_{SB1}	Automatic CE Power-Down Current —TTL Inputs	Max. V_{CC}, $\overline{CE}$ ≥ V_{IH} V_{IN} ≥ V_{IH} or V_{IN} ≤ V_{IL}, f = f_{MA}	Com	LL			2.5			1.5	mA
I_{SB2}	Automatic CE Power-Down Current —CMOS Inputs	Max. V_{CC}, $\overline{CE}$ ≥ V_{CC} – 0.3V, V_{IN} ≥ V_{CC} – 0.3V, or V_{IN} ≤ 0.3V, f=0	Com	LL		4	20		4	20	µA

Capacitance[4]

Parameter	Description	Test Conditions	Max.	Unit
C_{IN}	Input Capacitance	T_A = 25°C, f = 1 MHz, V_{CC} = 5.0V	6	pF
C_{OUT}	Output Capacitance		8	pF

Note:
3. Typical values are measured at V_{CC} = 5V, T_A = 25°C, and are included for reference only and are not tested or guaranteed.
4. Tested initially and after any design or process changes that may affect these parameters.

AC Test Loads and Waveforms



Switching Characteristics[5] Over the Operating Range

Parameter	Description	CY62148BLL-55		62148BLL–70		Unit
		Min.	Max.	Min.	Max.	
READ CYCLE						
t_{RC}	Read Cycle Time	55		70		ns
t_{AA}	Address to Data Valid		55		70	ns
t_{OHA}	Data Hold from Address Change	10		10		ns
t_{ACE}	$\overline{CE}$ LOW to Data Valid		55		70	ns
t_{DOE}	$\overline{OE}$ LOW to Data Valid		25		35	ns
t_{LZOE}	$\overline{OE}$ LOW to Low Z[6]	5		5		ns
t_{HZOE}	$\overline{OE}$ HIGH to High Z[6, 7]		20		25	ns
t_{LZCE}	$\overline{CE}$ LOW to Low Z[6]	10		10		ns
t_{HZCE}	$\overline{CE}$ HIGH to High Z[6, 7]		20		25	ns
t_{PU}	$\overline{CE}$ LOW to Power-Up	0		0		ns
t_{PD}	$\overline{CE}$ HIGH to Power-Down		55		70	ns
WRITE CYCLE[8]						
t_{WC}	Write Cycle Time	55		70		ns
t_{SCE}	$\overline{CE}$ LOW to Write End	45		60		ns
t_{AW}	Address Set-Up to Write End	45		60		ns
t_{HA}	Address Hold from Write End	0		0		ns
t_{SA}	Address Set-Up to Write Start	0		0		ns
t_{PWE}	$\overline{WE}$ Pulse Width	45		55		ns
t_{SD}	Data Set-Up to Write End	30		30		ns
t_{HD}	Data Hold from Write End	0		0		ns
t_{LZWE}	$\overline{WE}$ HIGH to Low Z[6]	5		5		ns
t_{HZWE}	$\overline{WE}$ LOW to High Z[6, 7]		20		25	ns

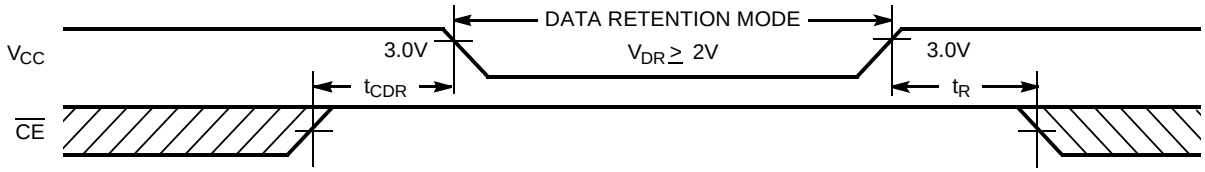
Notes:

5. Test conditions assume signal transition time of 5 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I_{OL}/I_{OH} and 100-pF load capacitance.
6. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZOE} is less than t_{LZOE}, and t_{HZWE} is less than t_{LZWE} for any given device.
7. t_{HZOE}, t_{HZCE}, and t_{HZWE} are specified with a load capacitance of 5 pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage.
8. The internal write time of the memory is defined by the overlap of $\overline{CE}_1$ LOW, and $\overline{WE}$ LOW. $\overline{CE}$ and $\overline{WE}$ must be LOW to initiate a write, and the transition of any of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write.

Data Retention Characteristics (Over the Operating Range)

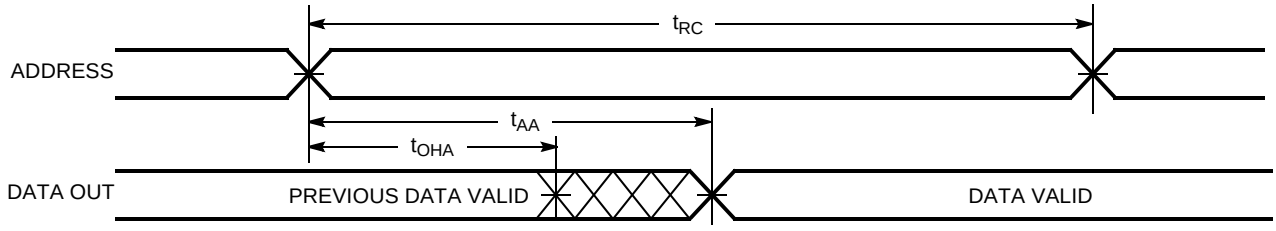
Parameter	Description			Conditions	Min.	Typ.[2]	Max.	Unit
V_{DR}	V_{CC} for Data Retention				2.0			V
I_{CCDR}	Data Retention Current	Com'l	LL	No input may exceed V_{CC} + 0.3V V_{CC} = V_{DR} = 3.0V $\overline{CE}$ > V_{CC} – 0.3V V_{IN} > V_{CC} – 0.3V or V_{IN} < 0.3V			20	µA
		Ind'l	LL				20	µA
t_{CDR}[4]	Chip Deselect to Data Retention Time				0			ns
t_R	Operation Recovery Time				t_{RC}			ns

Data Retention Waveform

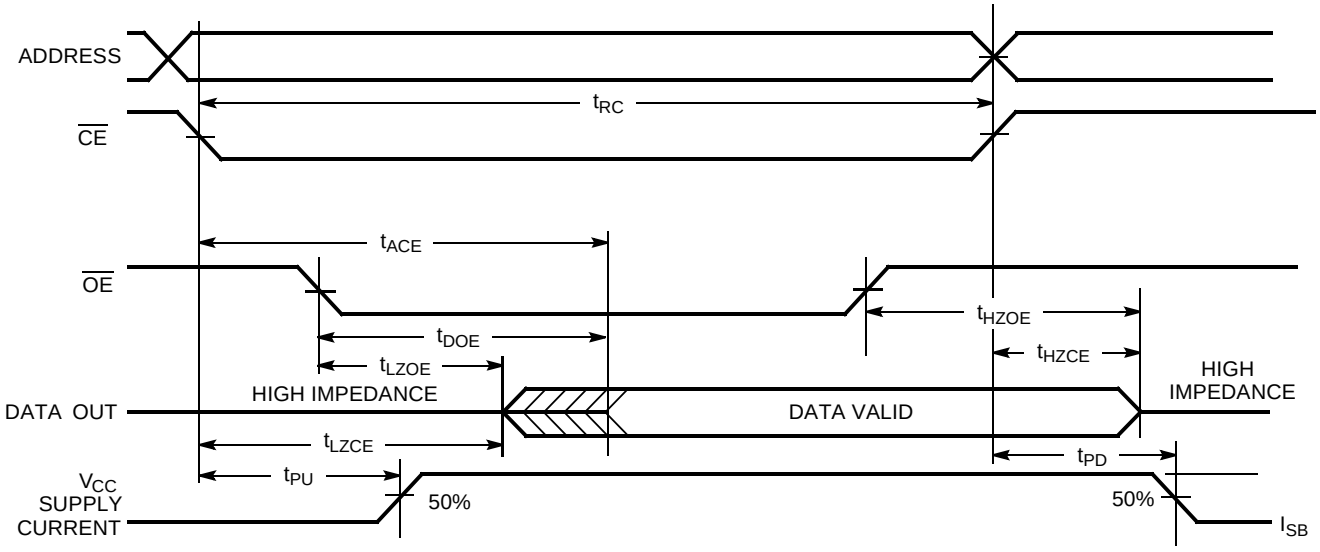


Switching Waveforms

Read Cycle No.1[9, 10]



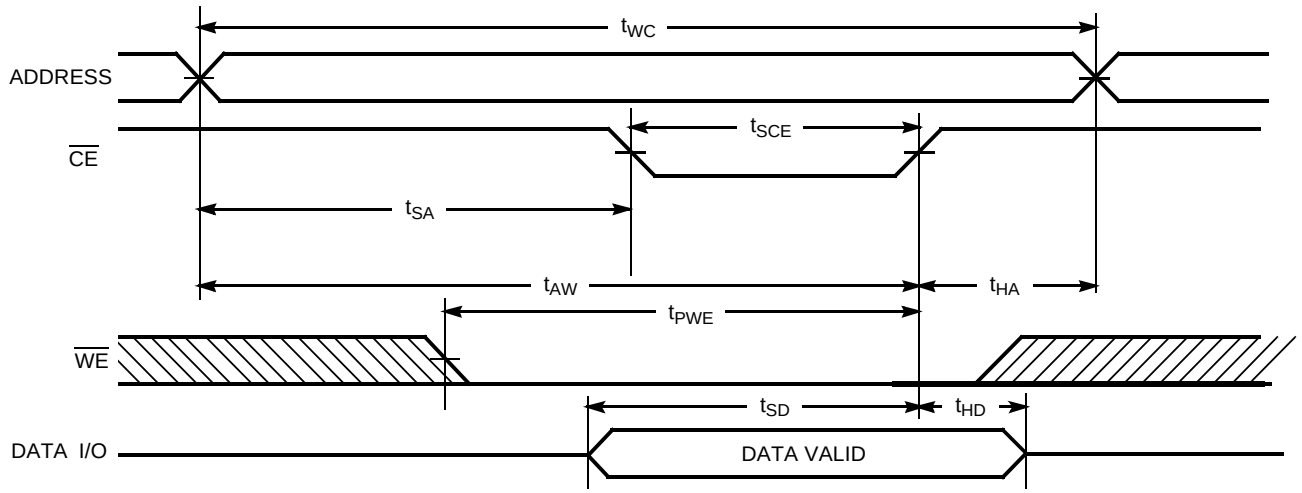
Read Cycle No. 2 ($\overline{OE}$ Controlled)[10, 11]



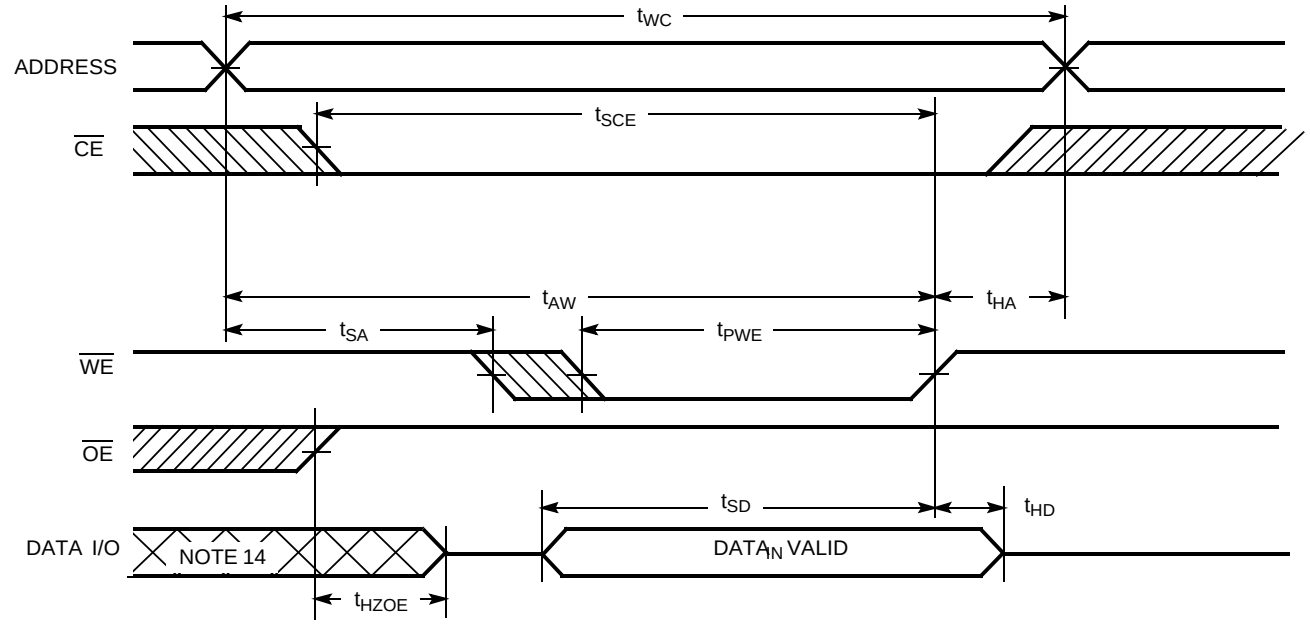
Notes:
9. Device is continuously selected. $\overline{OE}$, $\overline{CE}$ = V_{IL}.
10. $\overline{WE}$ is HIGH for read cycle.
11. Address valid prior to or coincident with $\overline{CE}$ transition LOW.

Switching Waveforms (continued)

Write Cycle No. 1 ($\overline{CE}$ Controlled)[12]



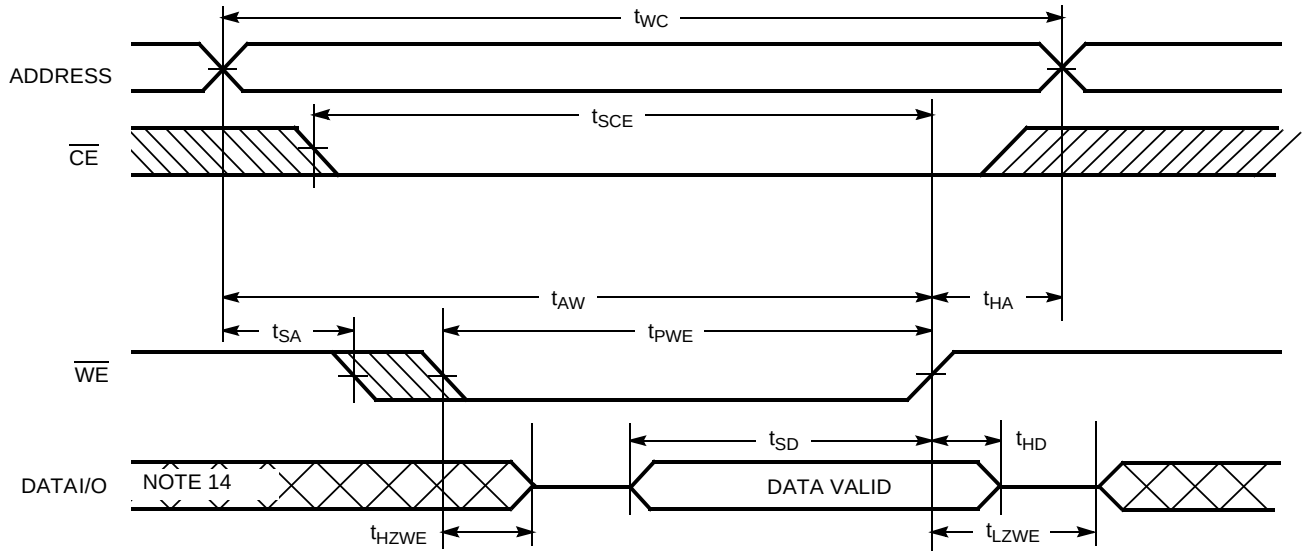
Write Cycle No. 2 ($\overline{WE}$ Controlled, $\overline{OE}$ HIGH During Write)[12, 13]



Notes:
12. If $\overline{CE}$ goes HIGH simultaneously with $\overline{WE}$ going HIGH, the output remains in a high-impedance state.
13. Data I/O is high-impedance if $\overline{OE} = V_{IH}$.
14. During this period the I/Os are in the output state and input signals should not be applied.

Switching Waveforms (continued)

Write Cycle No.3 ($\overline{WE}$ Controlled, $\overline{OE}$ LOW)[12, 13]



Truth Table

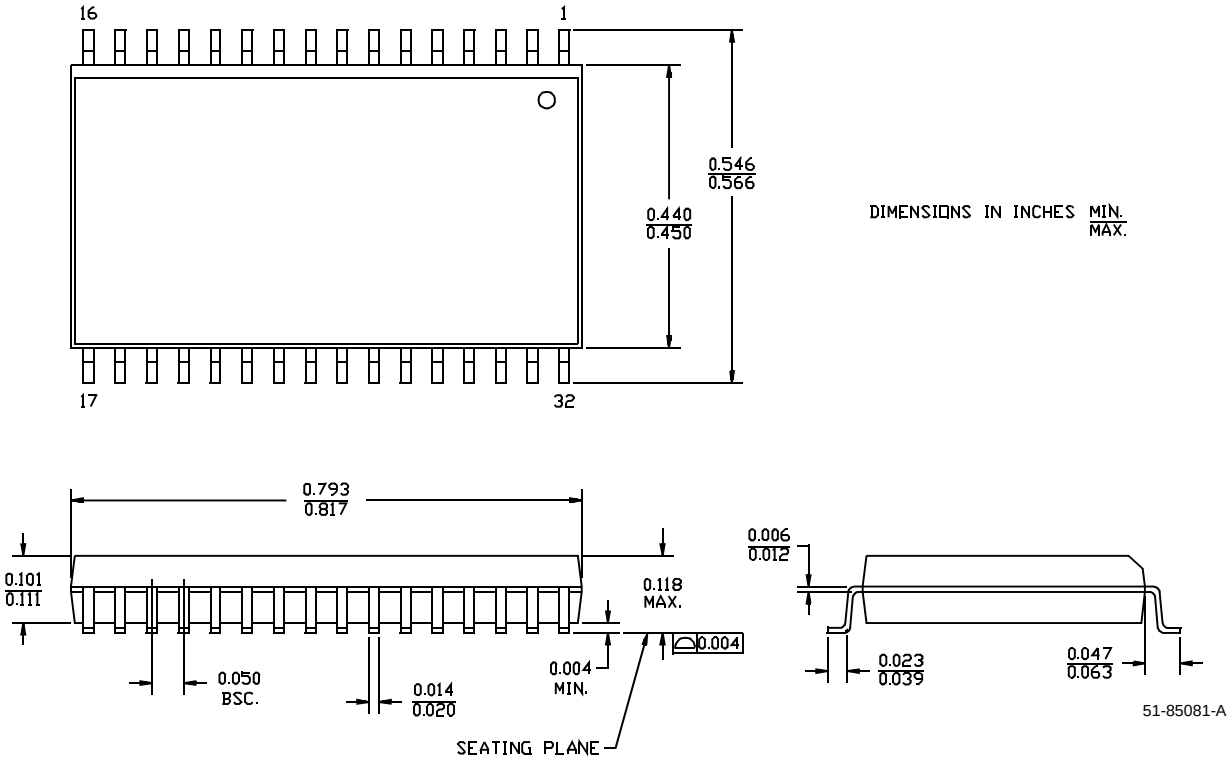
$\overline{CE}$	$\overline{OE}$	$\overline{WE}$	$I/O_0 – I/O_7$	Mode	Power
H	X	X	High Z	Power-Down	Standby (I_{SB})
L	L	H	Data Out	Read	Standby (I_{CC})
L	X	L	Data In	Write	Active (I_{CC})
L	H	H	High Z	Selected, Outputs Disabled	Active (I_{CC})

Ordering Information

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
70	CY62148BLL-70SC	S34	32-Lead (450-Mil) Molded SOIC	Commercial
	CY62148BLL-70ZC	ZS32	32-Lead TSOP II	
	CY62148BLL-70ZRC	ZU32	32-Lead RTSOP II	
	CY62148BLL-70SI	S34	32-Lead (450-Mil) Molded SOIC	Industrial
	CY62148BLL-70ZI	ZS32	32-Lead TSOP II	
	CY62148BLL-70ZRI	ZU32	32-Lead RTSOP II	
55	CY62148BLL-55SC	S34	32-Lead (450-Mil) Molded SOIC	Commercial
	CY62148BLL-55ZC	ZS32	32-Lead TSOP II	
	CY62148BLL-55ZRC	ZU3s	32-Lead RTSOP II	
	CY62148BLL-55SI	S34	32-Lead (450-Mil) Molded SOIC	Industrial
	CY62148BLL-55ZI	ZS32	32-Lead TSOP II	
	CY62148BLL-55ZRI	ZU32	32-Lead RTSOP II	

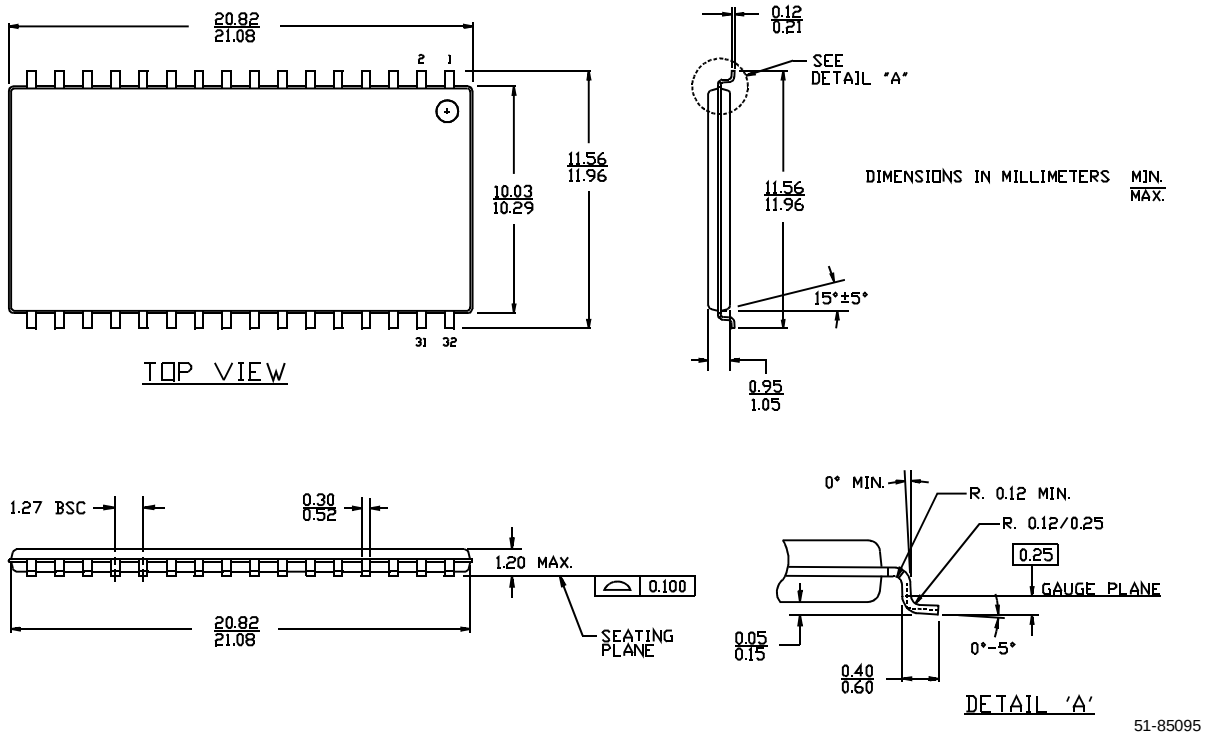
Package Diagrams

32-Lead (450 MIL) Molded SOIC S34



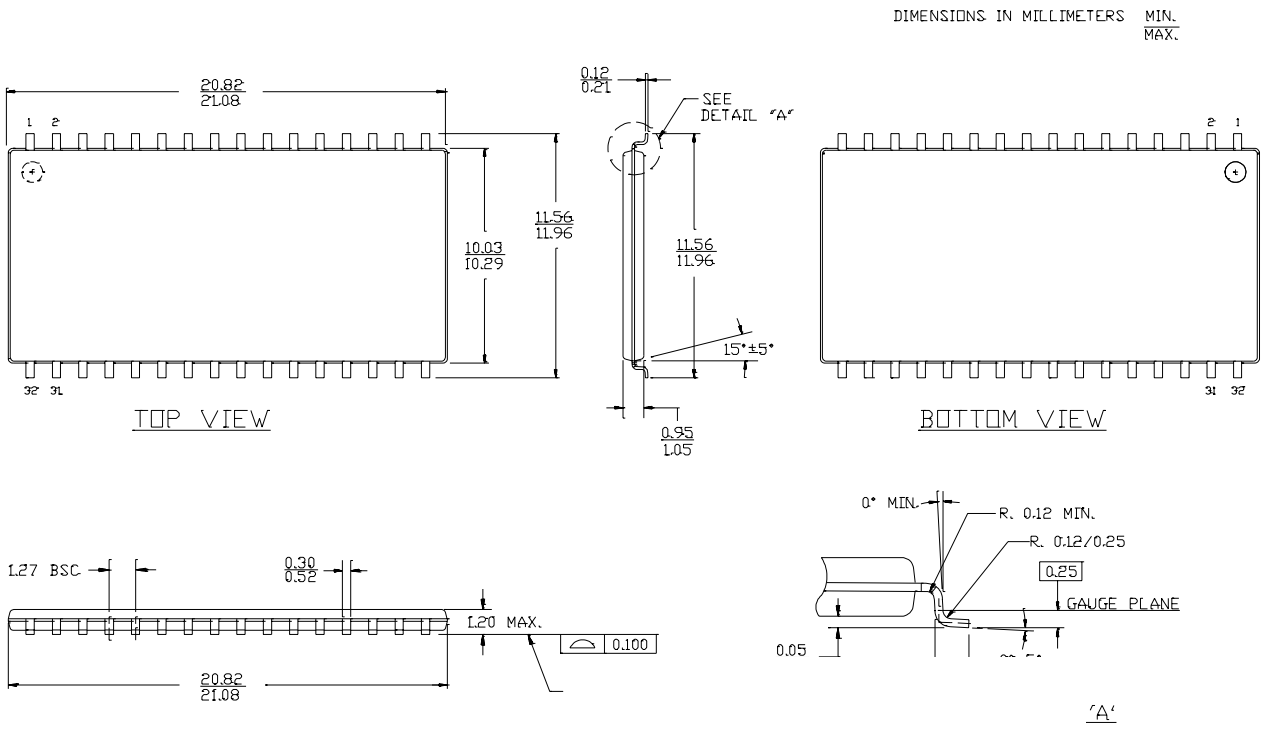
Package Diagrams (continued)

32-Lead TSOP II ZS32



Package Diagrams (continued)

32-Lead Reverse Thin Small Outline Package Type II ZU32



Document Title: CY62148B 512K x 8 Static RAM Document Number: 38-05039				
REV.	**ECN NO.**	**Issue Date**	**Orig. of Change**	**Description of Change**
**	106833	05/01/01	SZV	Change from Spec number 38-01104 to 38-05039
*A	106970	07/16/01	GAV	Modified annotations on Pin Configurations; t_{SD} = 30 ns